

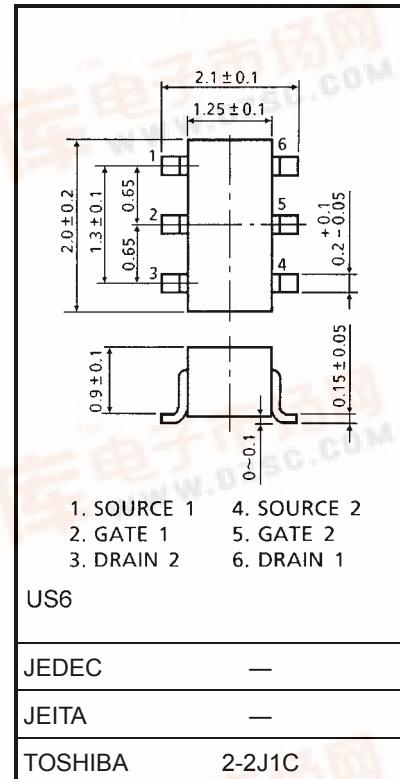
TOSHIBA Field Effect Transistor Silicon N Channel MOS Type

HN1K04FU

High Speed Switching Applications

Analog Switch Applications

Unit: mm



Note: TOTAL rating

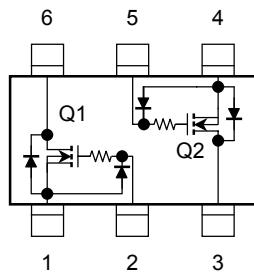
Weight: 6.8 mg

Electrical Characteristics (Ta = 25°C) (Q1, Q2 common)

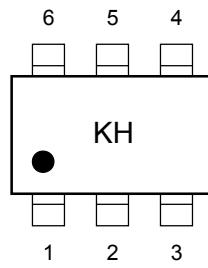
Characteristic	Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current	I _{GSS}	V _{GS} = 10 V, V _{DS} = 0 V	—	—	1	μA
Drain-source breakdown voltage	V _{(BR) DSS}	I _D = 100 μA, V _{GS} = 0 V	50	—	—	V
Drain cut-off current	I _{DSS}	V _{DS} = 50V, V _{GS} = 0 V	—	—	1	μA
Gate threshold voltage	V _{th}	V _{DS} = 5V, I _D = 0.1 mA	0.8	—	2.5	V
Forward transfer admittance	Y _{fs}	V _{DS} = 5V, I _D = 10 mA	20	—	—	mS
Drain-source ON resistance	R _{DS} (ON)	I _D = 10 mA, V _{GS} = 4.0 V	—	20	50	Ω
Input capacitance	C _{iss}	V _{DS} = 5 V, V _{GS} = 0 V, f = 1 MHz	—	6.3	—	pF
Reverse transfer capacitance	C _{rss}	V _{DS} = 5 V, V _{GS} = 0 V, f = 1 MHz	—	1.3	—	pF
Output capacitance	C _{oss}	V _{DS} = 5 V, V _{GS} = 0 V, f = 1 MHz	—	5.7	—	pF
Switching time	t _{on}	V _{DD} = 5 V, I _D = 10 mA, V _{GS} = 0 to 4.0 V	—	0.11	—	μs
	t _{off}	V _{DD} = 5 V, I _D = 10 mA, V _{GS} = 0 to 4.0 V	—	0.15	—	

Equivalent Circuit (top view)

Marking

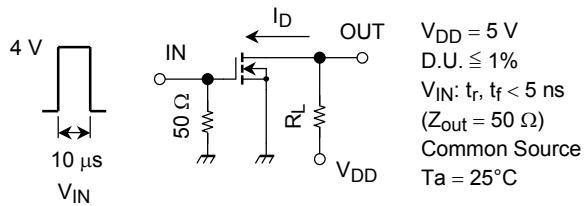


(Q1, Q2 common)



Switching Time Test Circuit

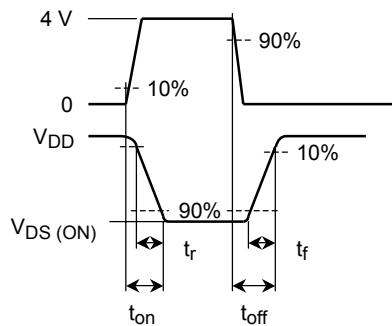
(a) Test circuit



$V_{DD} = 5 \text{ V}$
 $D.U. \leq 1\%$
 $V_{IN}: t_r, t_f < 5 \text{ ns}$
 $(Z_{out} = 50 \Omega)$
 Common Source
 $T_a = 25^\circ\text{C}$

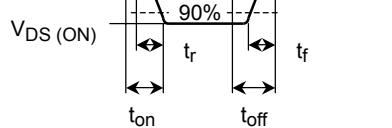
(b) V_{IN}

V_{GS}

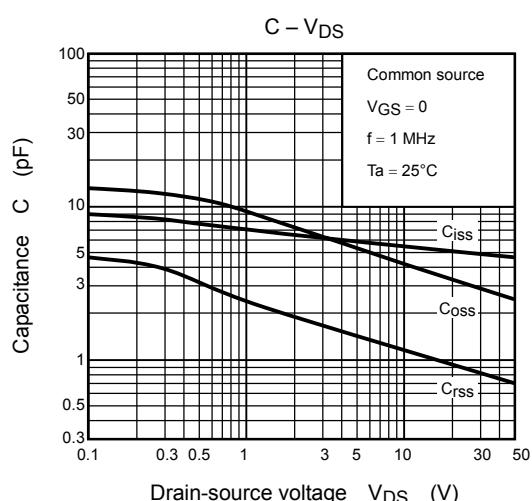
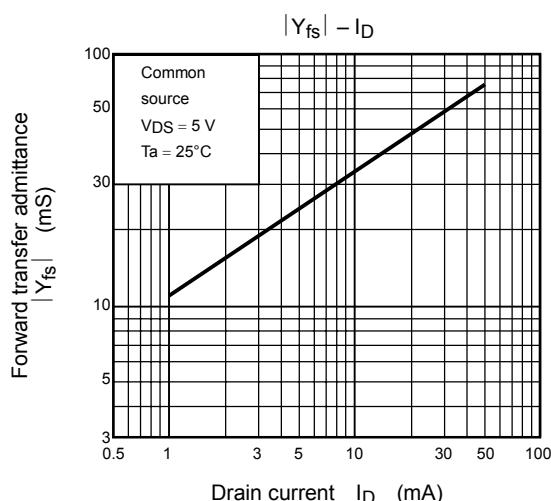
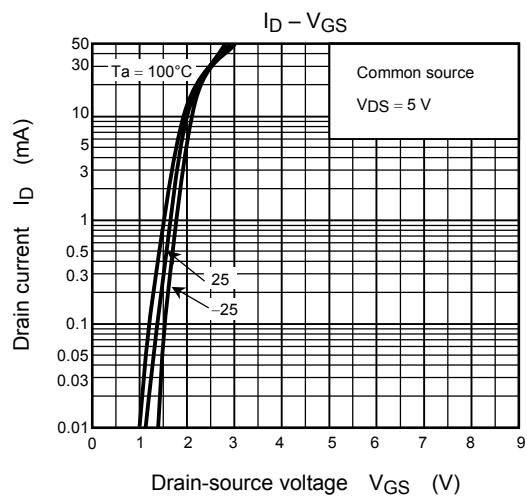
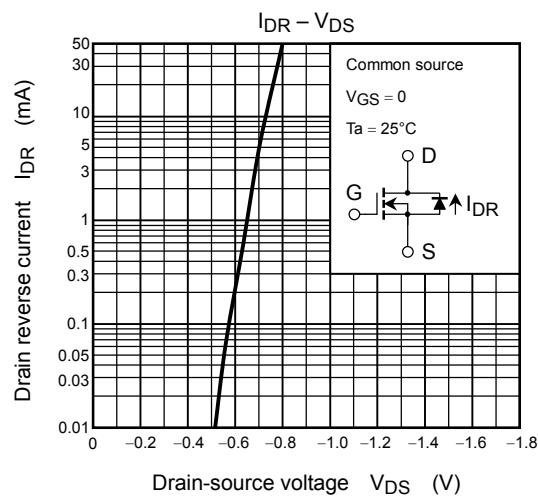
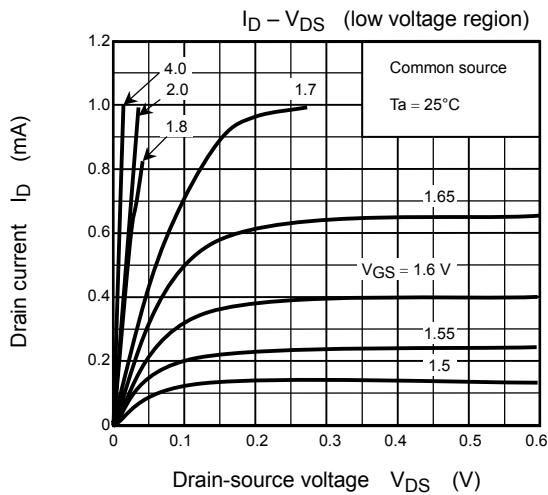
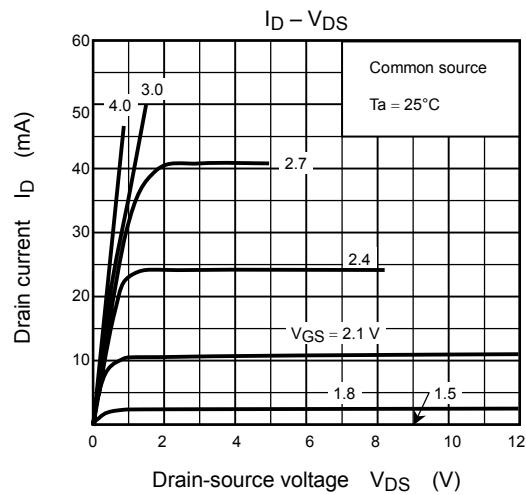


(c) V_{OUT}

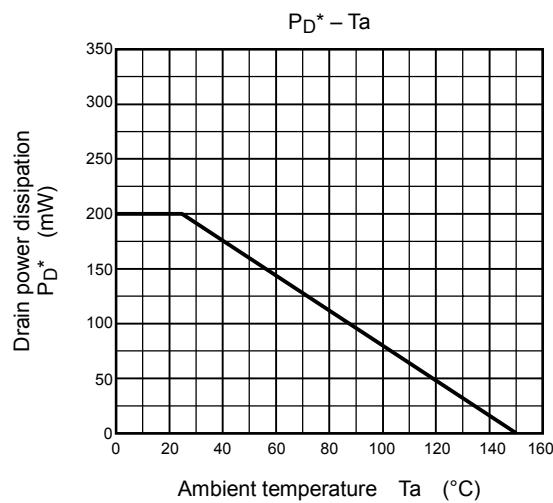
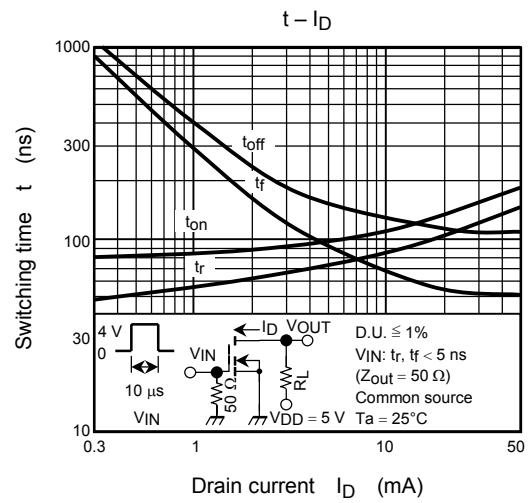
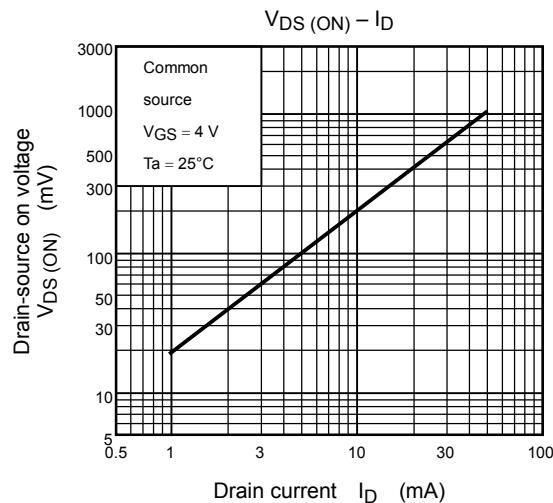
V_{DS}



(Q1, Q2 common)



(Q1, Q2 common)



*: TOTAL rating

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